

Inventor:
Serial No.:
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Docket No.:
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Soo Young Choi et al.
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Controlling the Properties and Uniformity . . .
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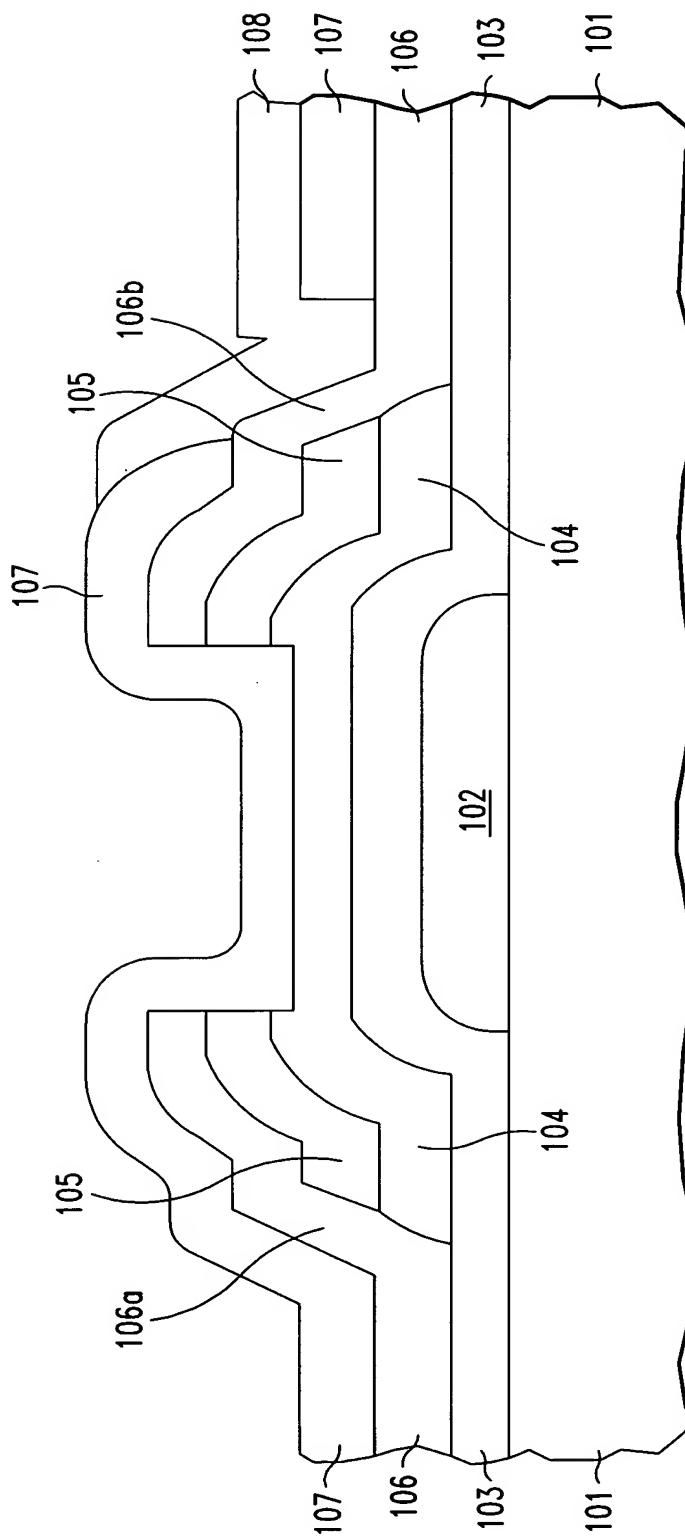
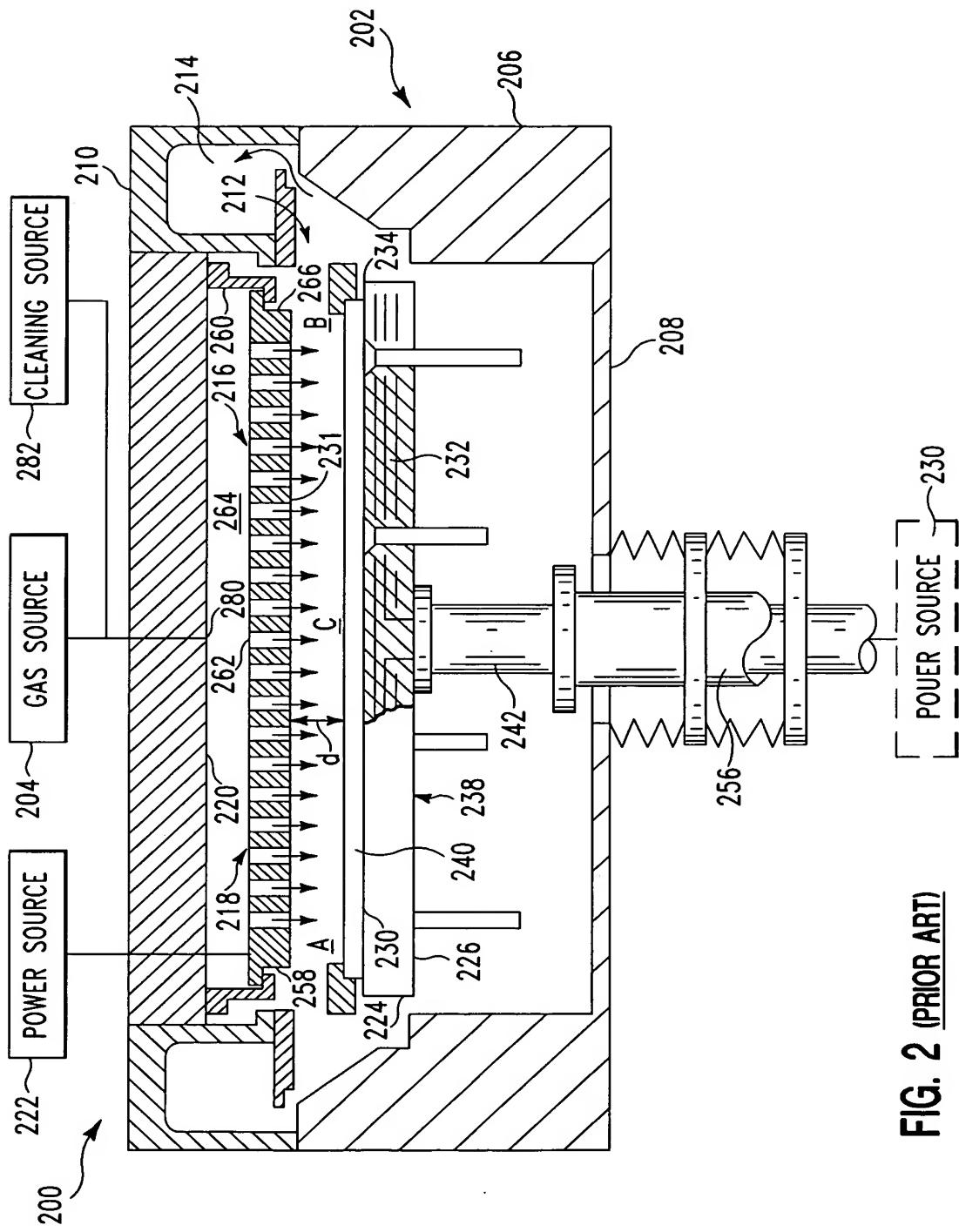


FIG. 1A (PRIOR ART)



300 {
 ITO Pattern(MASK5)
 ITO Sputtering
 Passivation Etch(MASK4)
 SiNx PECVD
 n+ a-Si Etch-Back
 S/D Pattern(MASK3)
 S/D Sputtering
 a-Si Pattern(MASK2)
 n+a-Si/a-Si/SiNx PECVD
 Gate Pattern(MASK1)
 Gate Metal Sputtering

FIG. 3A

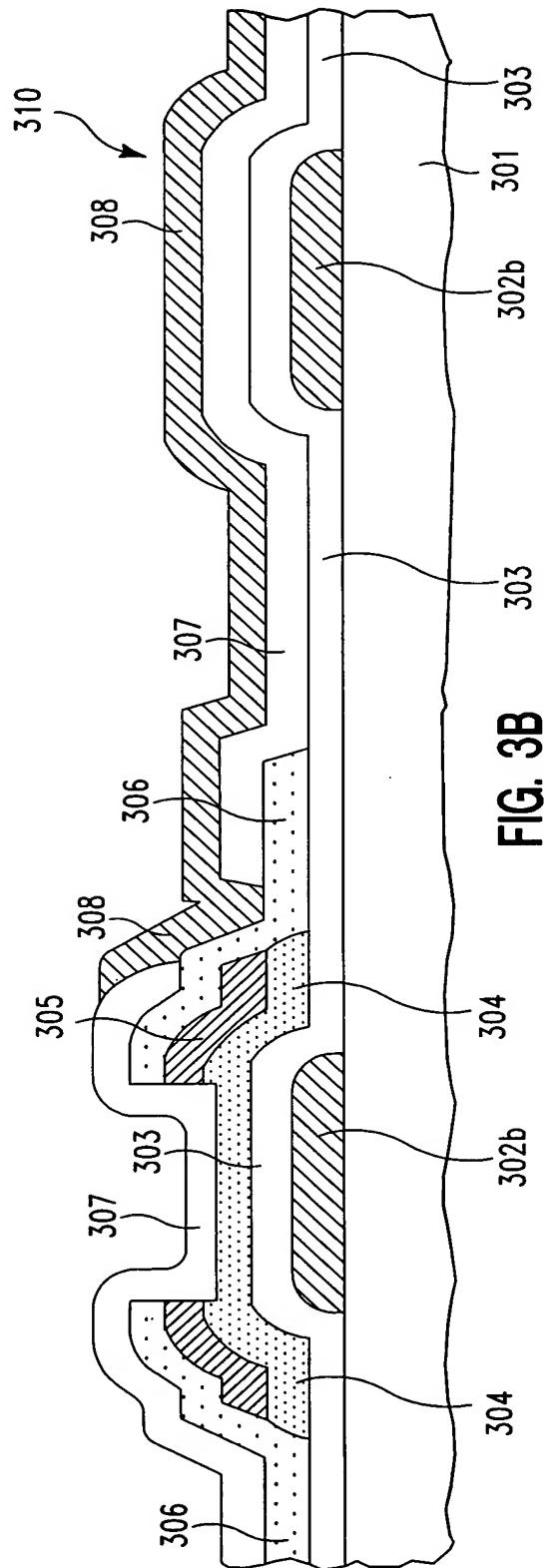
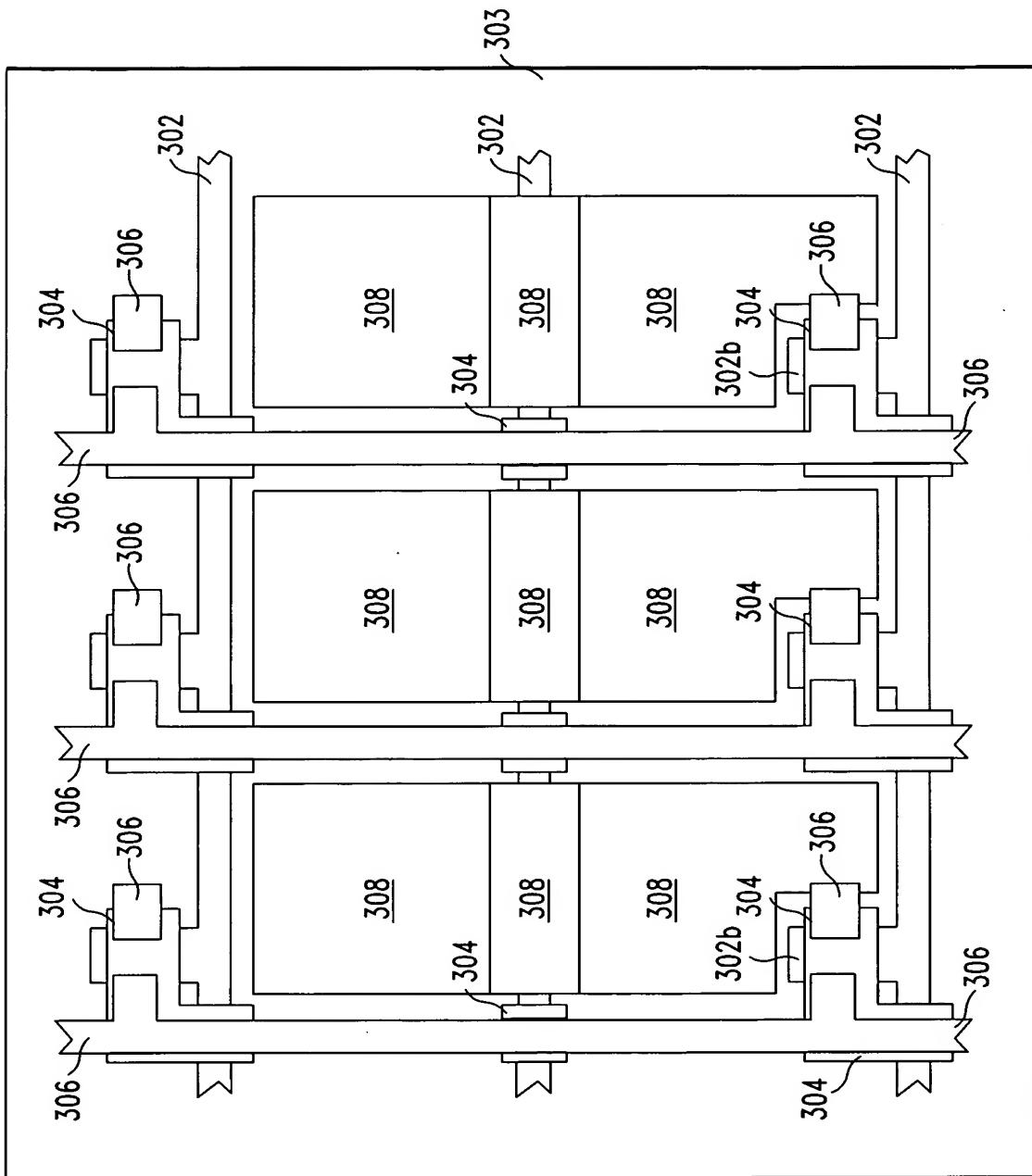


FIG. 3B

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FIG. 3C

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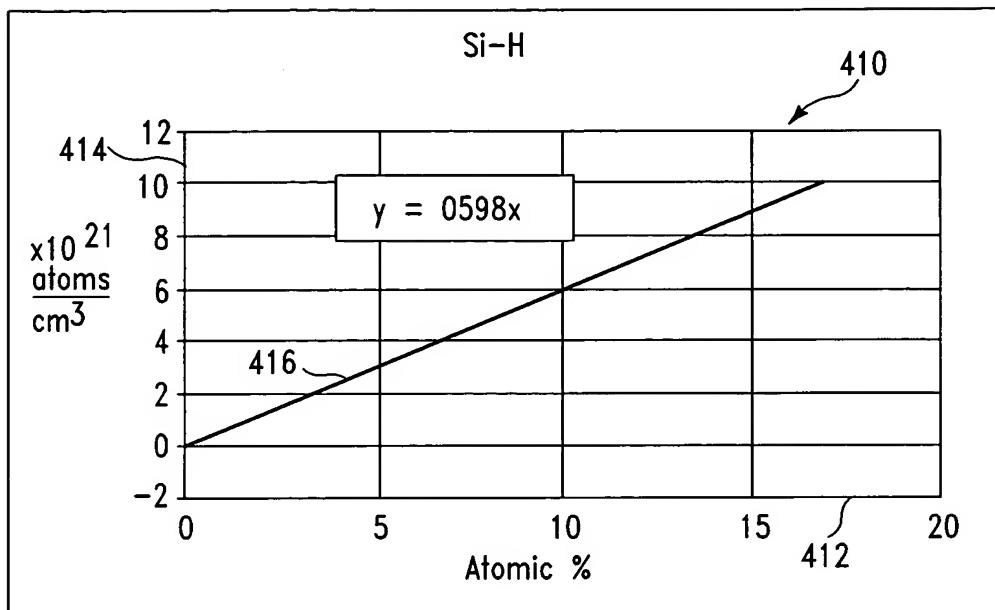


FIG. 4A

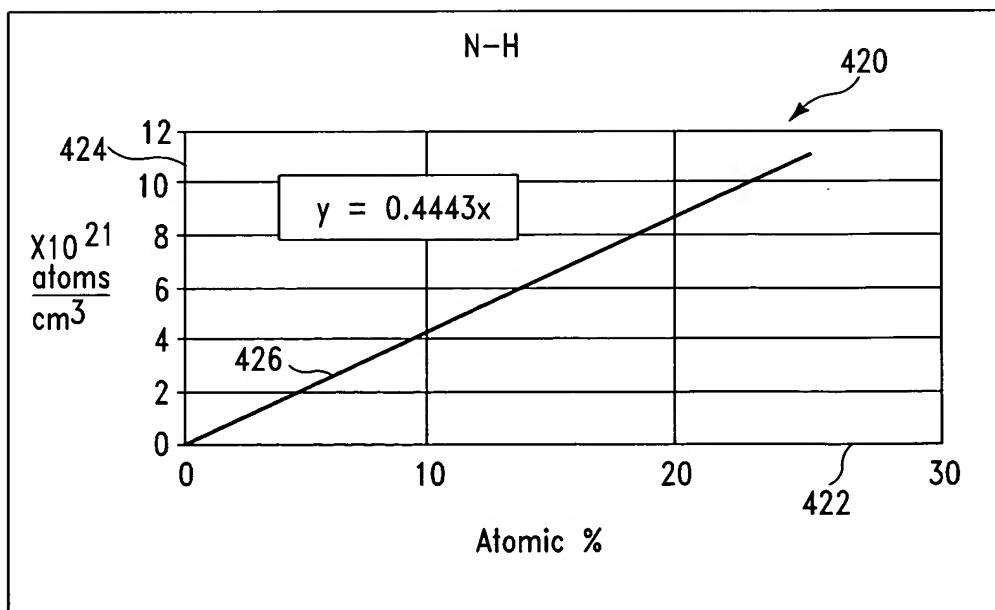


FIG. 4B